

The 2021 International Workshop on the High Energy Circular Electron Positron Collider  
Nanjing, Nov. 8-12, 2021

# **Status report about the Chinese projects on MAPS for vertexing at CEPC**

Ying Zhang and [Yunpeng Lu](#)

On behalf of the CMOS pixel sensor teams  
for the MOST1 & MOST2 projects

Nov. 8, 2021



# Outline

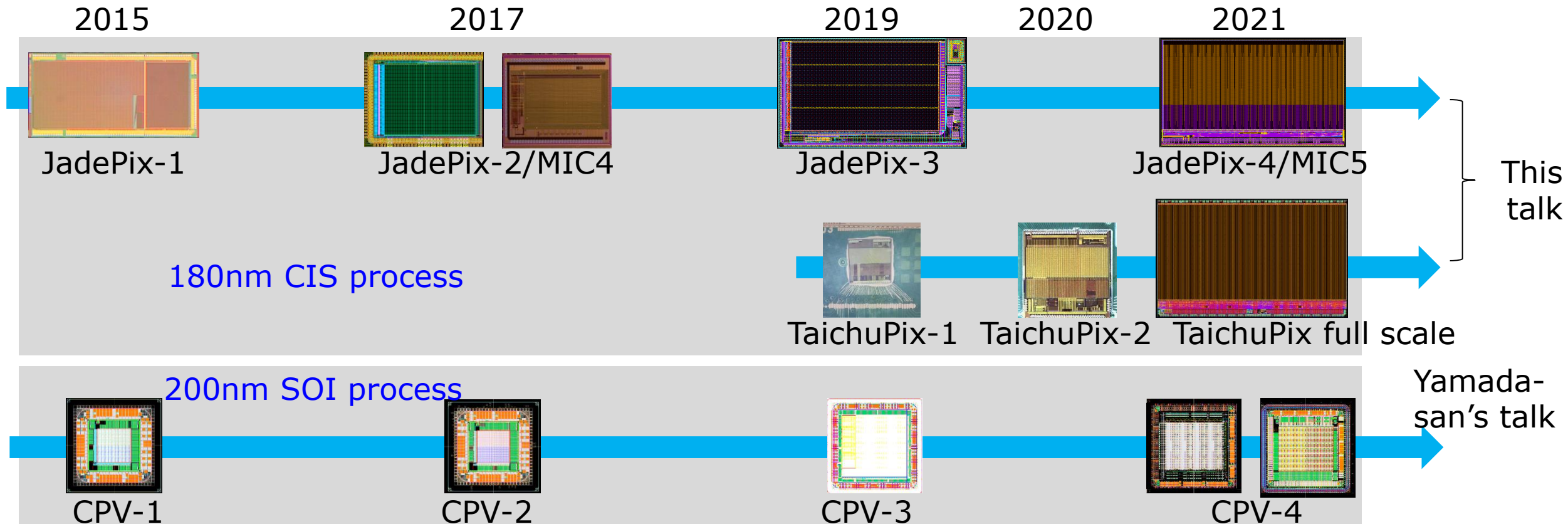
- Overview of pixel sensor development
- Update on the JadePix
  - JadePix-3 test
  - JadePix-4 design
- Update on the TaichuPix
  - TaichuPix-2 test
  - TaichuPix full scale design
- Summary



# Projects in China

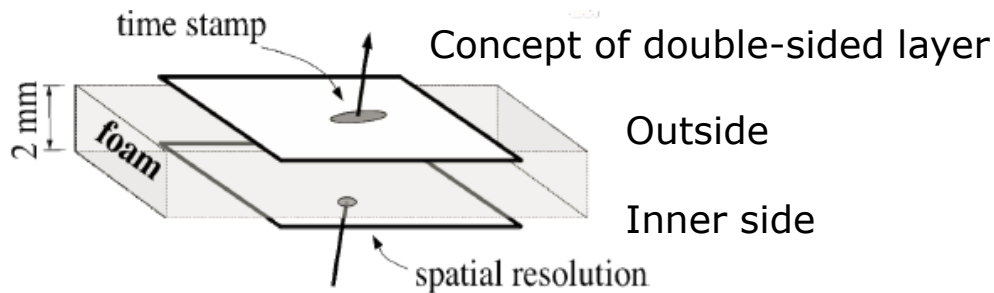
■ Development of pixel sensor for CEPC are supported by

- Ministry of Science and Technology (MOST)
- National Natural Science Foundation of China (NSFC)
- IHEP fund for innovation

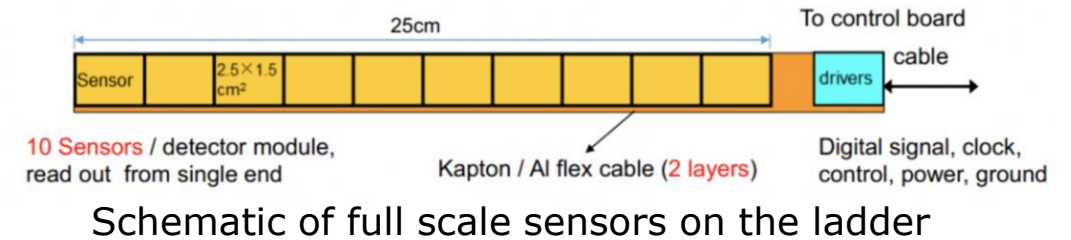


# Strategies to address the challenges

- JadePix sticks to a double-sided concept
  - Pitch, power, readout speed
  - A pair of complementary design envisioned



- TaichuPix stresses on the system level
  - Full scale prototype for ladder assembly
  - Fine time stamp & Radiation hardness to cope with Z-pole mode



Impact parameter resolution

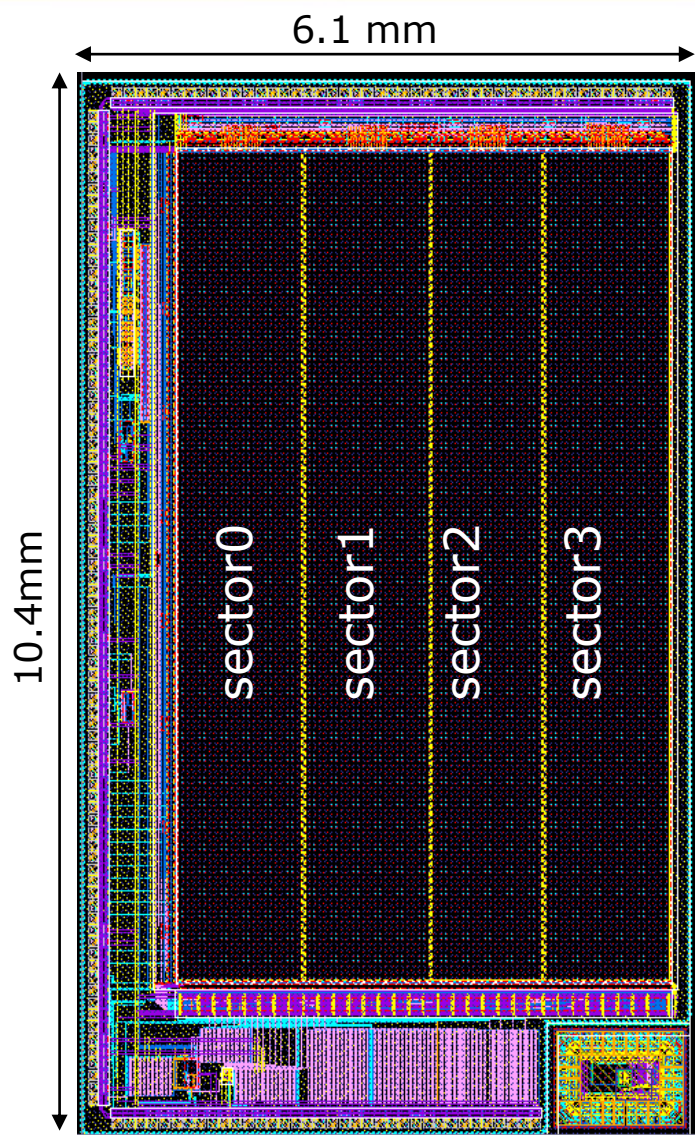
$$\sigma_{r\phi} = 5 \mu\text{m} \oplus \frac{10}{p(\text{GeV}) \sin^{3/2} \theta} \mu\text{m}$$

Vertex detector specs

$\sigma_{\text{s.p.}} \sim 2.8 \mu\text{m}$  -----> **Small pixel**  $\sim 16 \mu\text{m}$   
**Material budget**  $\sim 0.15\% X_0/\text{layer}$  -----> **Thinning to**  $\sim 50 \mu\text{m}$   
 -----> **low power**  $\sim 50 \text{mW}/\text{cm}^2$   
**r of Inner most layer**  $\sim 16 \text{mm}$  -----> **fast readout**  $\sim 1 \mu\text{s}$   
 -----> **radiation tolerance**  $\sim$   
 $\leq 3.4 \text{ Mrad}/\text{year}$   
 $\leq 6.2 \times 10^{12} n_{\text{eq}} / (\text{cm}^2 \text{ year})$



# JadePix-3 optimized for small pitch



- **Rolling shutter** to avoid heavy logic and routing in the column-wise
  - Shrink the pixel size by  $\sim 7 \mu\text{m}$
- **Full-sized** in the  $\varphi$  direction
  - Matrix coverage:  $16 \mu\text{m} * 512 \text{ rows} = 8.2 \text{ mm}$
  - Matrix readout time:  $192\text{ns/row} * 512 \text{ rows} = \mathbf{98.3 \mu\text{s/frame}}$
- **Extensible** in the z direction
  - $48 \text{ columns} * 4 \text{ sectors}$

Sector	Diode	Analog	Digital	Pixel layout
0	$2 + 2 \mu\text{m}$	FE_V0	DGT_V0	$16 \times 26 \mu\text{m}^2$
1	$2 + 2 \mu\text{m}$	FE_V0	DGT_V1	$16 \times 26 \mu\text{m}^2$
<b>2</b>	<b><math>2 + 2 \mu\text{m}</math></b>	<b>FE_V0</b>	<b>DGT_V2</b>	<b><math>16 \times 23.11 \mu\text{m}^2</math></b>
3	$2 + 2 \mu\text{m}$	FE_V1	DGT_V0	$16 \times 26 \mu\text{m}^2$



# Functional verification

Sheng DONG, Yang ZHOU, Ying ZHANG, Zhan SHI, Yunpeng LU

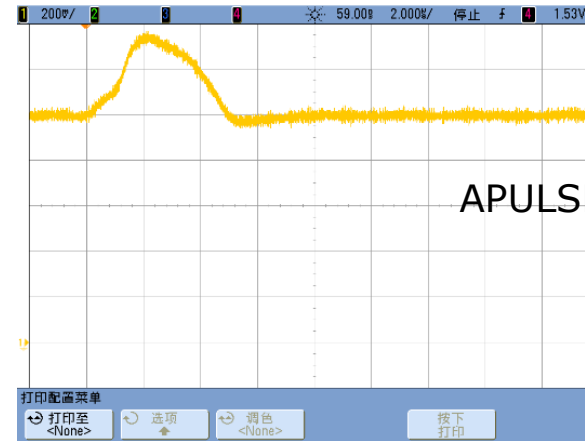
## ■ All module functions verified

- Configuration of matrix registers
- Configuration of Global DAC
- Pulse test
- Analog output waveform
- Data readout
- PLL clock
- Serializer output pattern

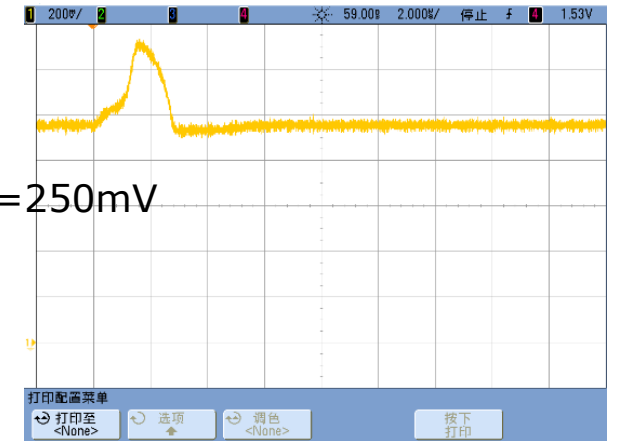
## ■ Response to the radiation as expected

- Radiative source  $^{55}\text{Fe}$
- Cosmic ray
- Pulsed laser beam

Low power frontend

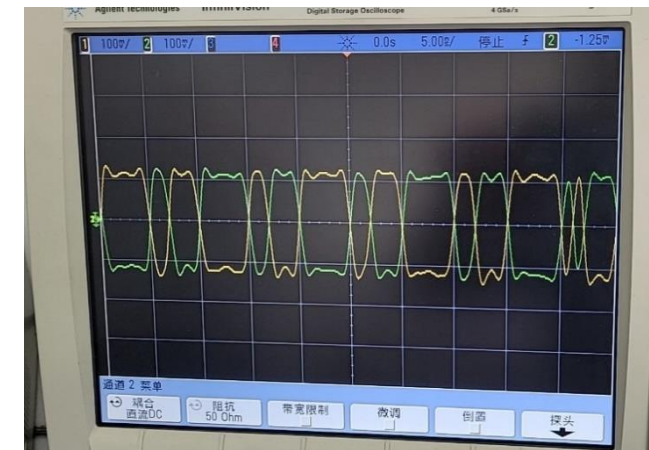
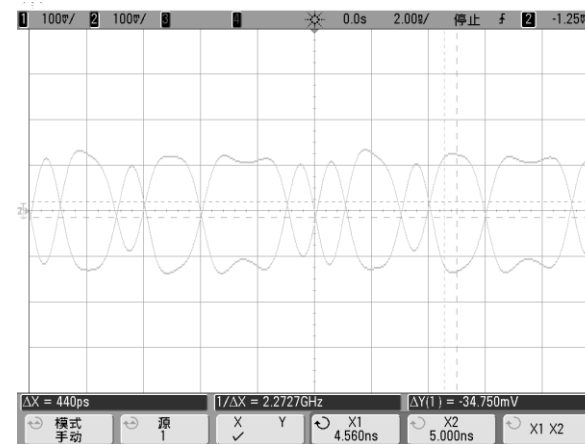


Radiation-enhanced frontend



APULSE=250mV

Output pattern of serializer @ 1Gbps

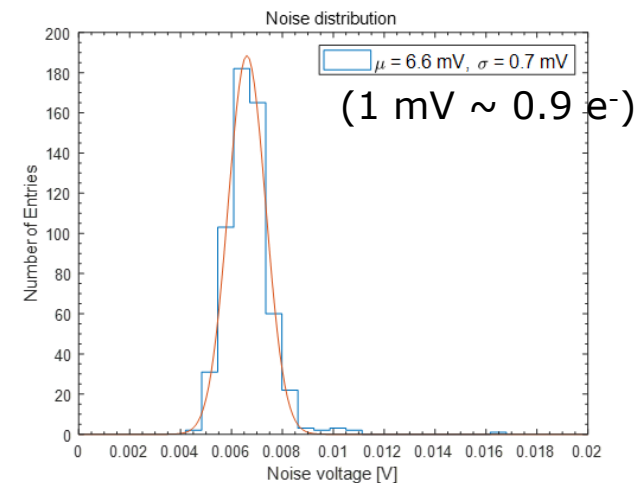
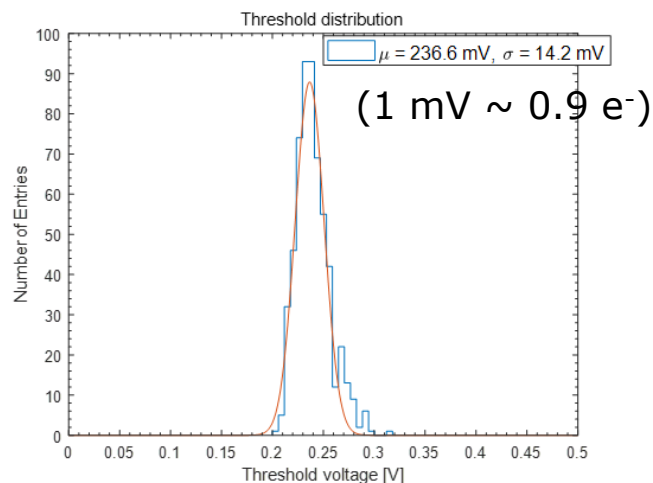
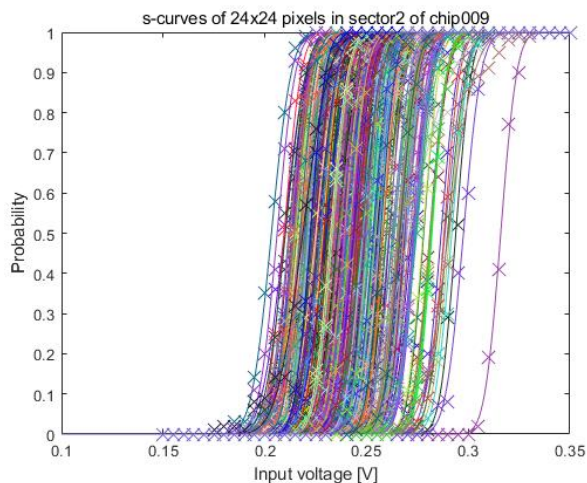


# Threshold and Noise (Electrical pulse test)

Ying ZHANG, Yang ZHOU, Jing DONG, Yunpeng LU

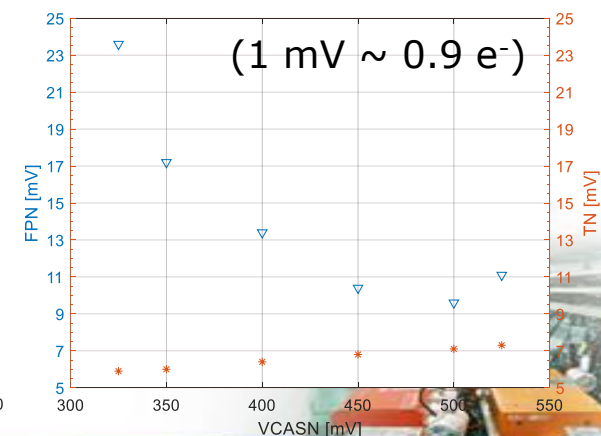
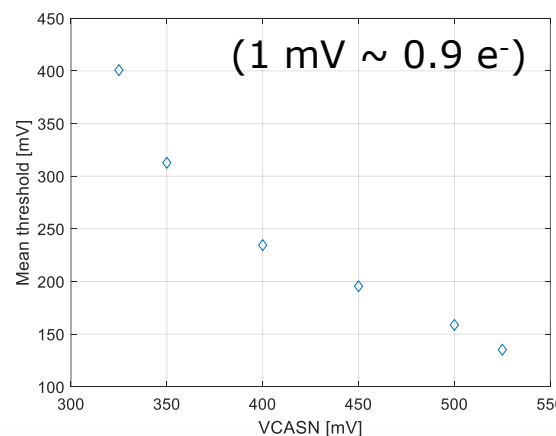
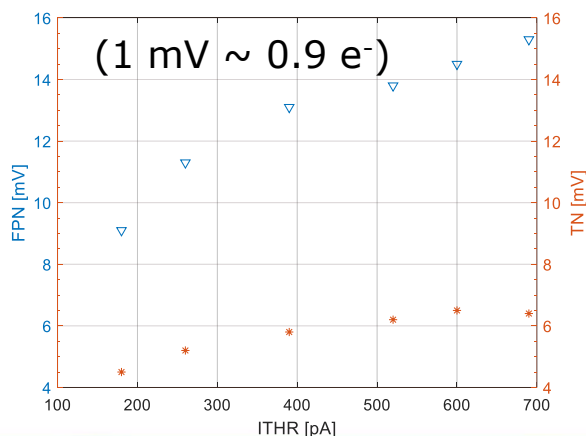
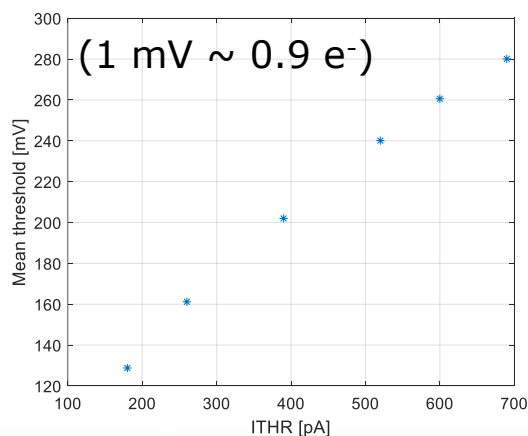
## ■ Pulse amplitude scan and **S-curve\*** fit @ nominal threshold

\*S-curve: cumulative Gaussian distribution



## ■ Input-referred threshold as a function of the parameters Ithr and Vcasn

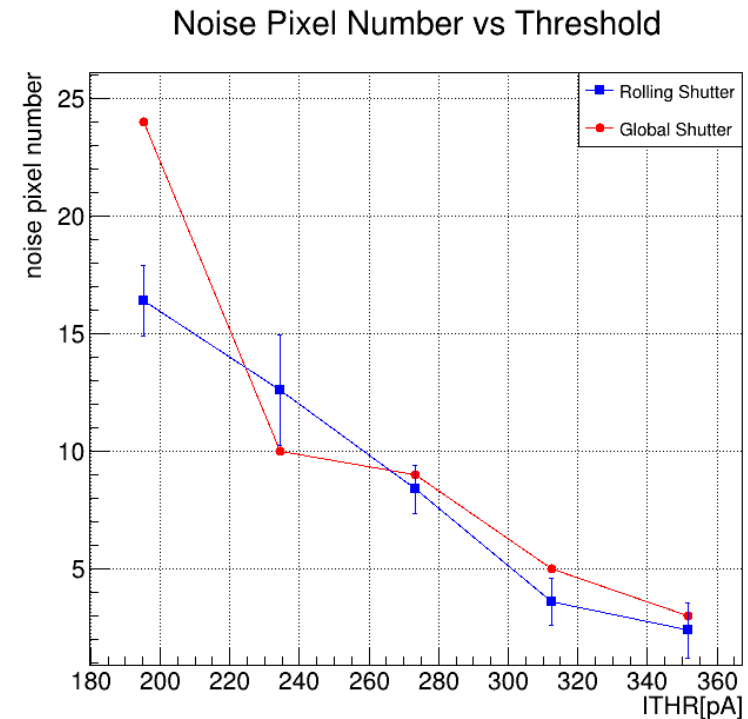
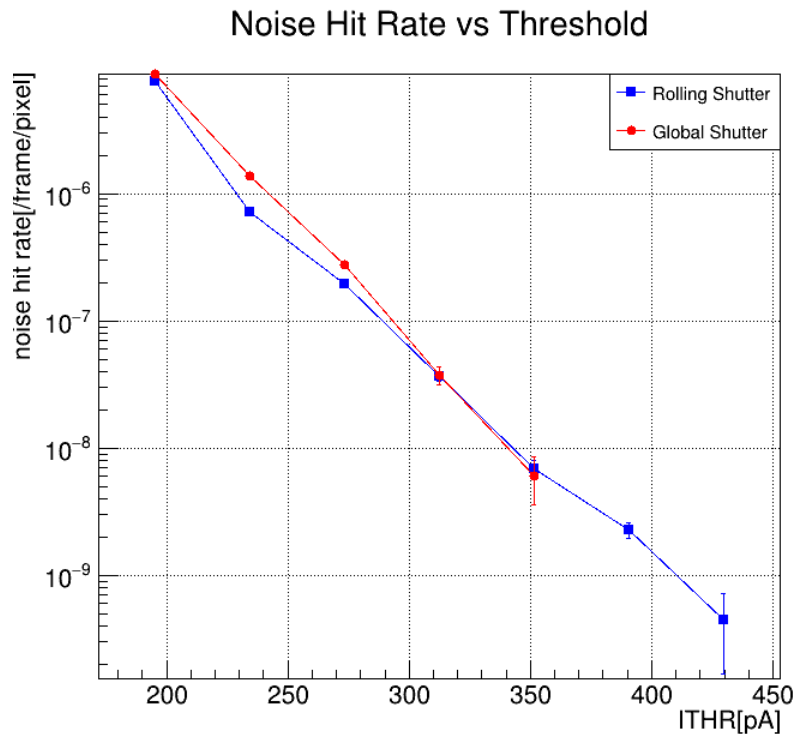
- Nominal threshold = 220e<sup>-</sup> @ Ithr = 0.5 nA, Vthr = 400 mV



# Noise hit rate

Chunhao Tian, Yunpeng LU

- Well below  $10^{-6}$  hits / pixel per frame (98.3  $\mu\text{s}$ )
  - Rolling shutter (**Continuous** readout mode) shows noise hit rate as low as the global shutter (**Single frame** readout mode)
  - No pixel masked

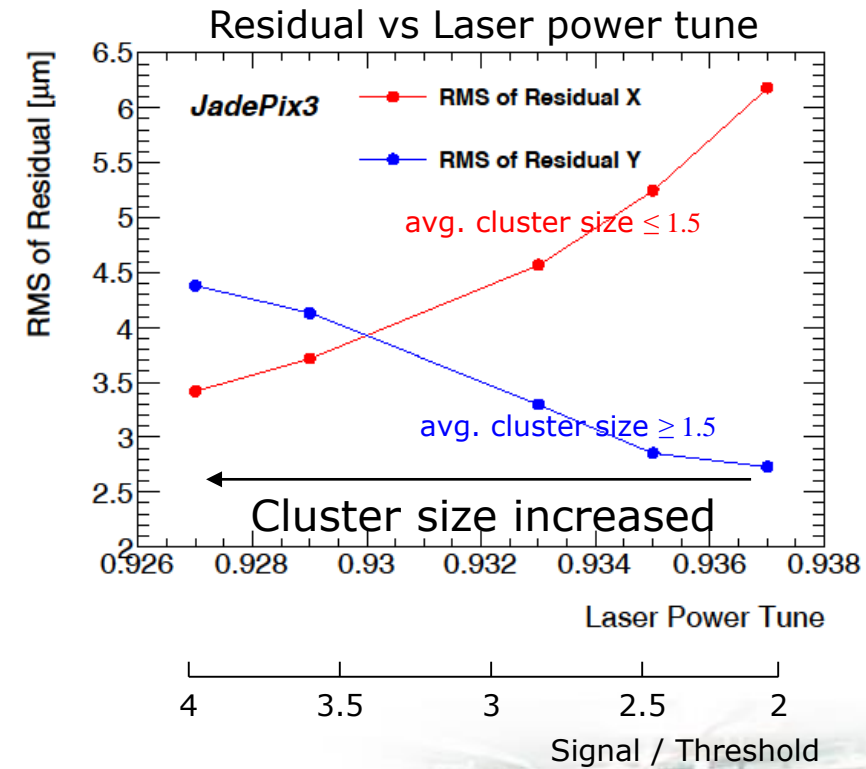
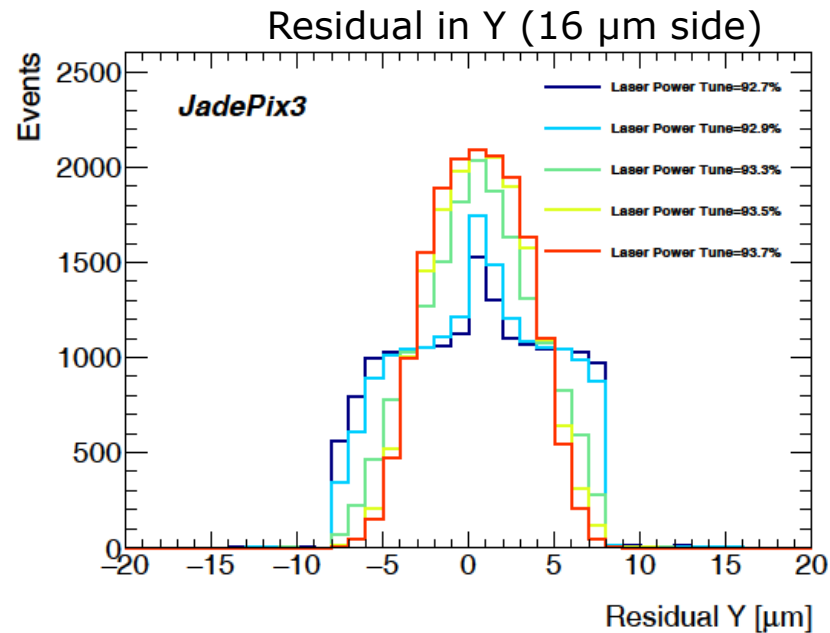
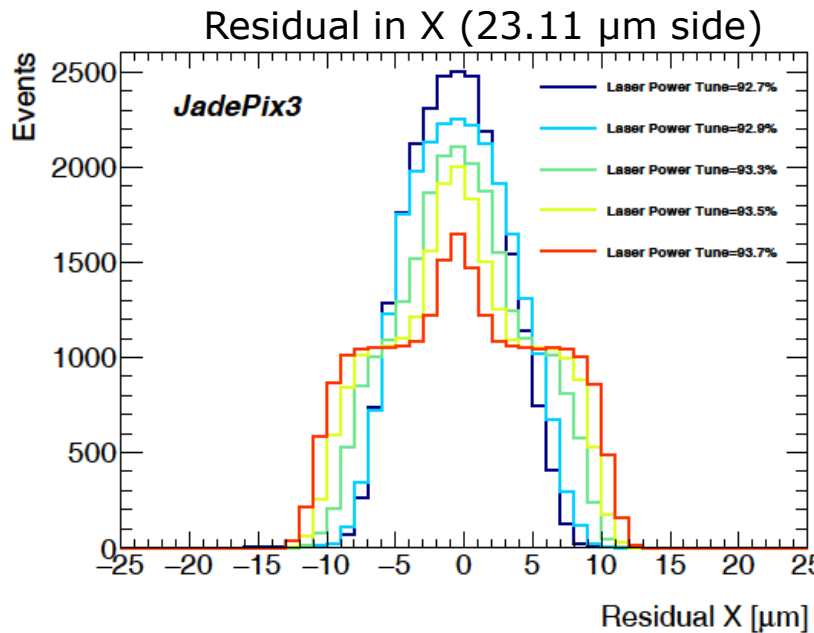




# Position resolution

Hulin WANG, Shen DONG, Yunpeng LU

- Threshold set to  $220e^-$ , tune the laser power to vary cluster size
  - Laser beam focused to  $d=3.4 \mu\text{m}$
- **Minimum value** as cluster size approaching 1.5
  - $3.34 \mu\text{m}$  @ signal =  $880e^-$  in X
  - $2.31 \mu\text{m}$  @ signal =  $440e^-$  in Y



# Power consumption

Ying ZHANG, Zhan SHI, Yunpeng LU

- Average power consumption with present chip size, **46.9 mW/cm<sup>2</sup>**
  - **1.04 \* 0.61 cm<sup>2</sup>**
  - PLL and Serializer not included (parallel bus for data output)
- Extrapolated to a full size chip, **91.44 mW/cm<sup>2</sup>**
  - **1 cm \* 2.56 cm**
  - PLL and Serializer included
- Could be cut off further
  - Analog buffer (1.8mA)
  - Alternative LVDS receiver (1.74mA)
  - PLL test output (11.5mA)

Extrapolation of average power consumption

	<b>512*192 (JadePix3)</b>	<b>512*1024 (Full-sized chip)</b>
Matrix	3.15 mA	16.79 mA
Zero suppression and data buffering	12.47 mA	66.47 mA
Shared modules	46.82 mA	46.82 mA
Sum	62.44 mA	130.08 mA

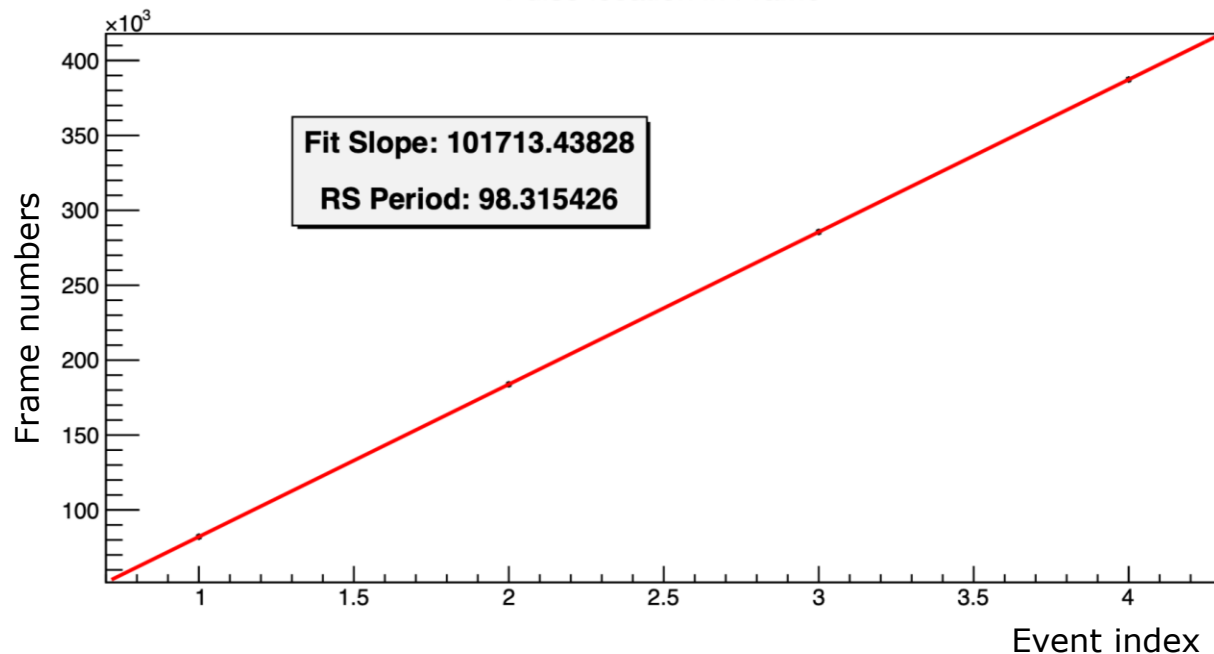


# Rolling Shutter Readout

Sheng DONG, Hulin WANG, Yunpeng LU

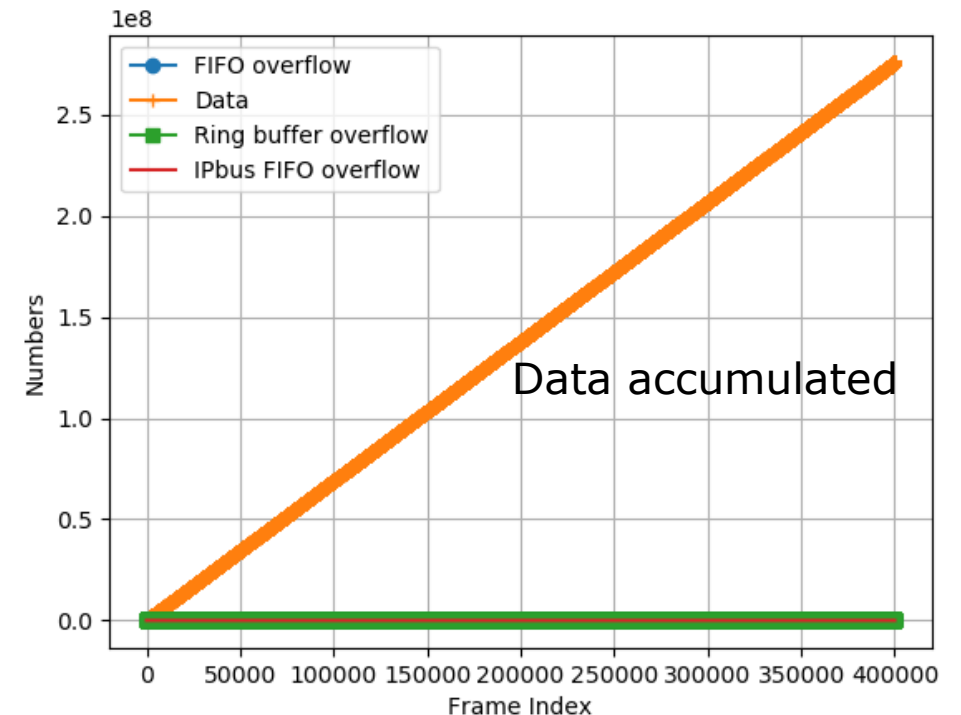
## ■ Frame period (**Integration time**)

- Event interval: 10 s
- Count the frame numbers between 2 events
- Frame period: **98.315  $\mu$ s**



## ■ Stability test

- Hit number per event: 2048
- Event interval: 110  $\mu$ s
- Data throughput: **595.8 Mbps \* 39.3 s**



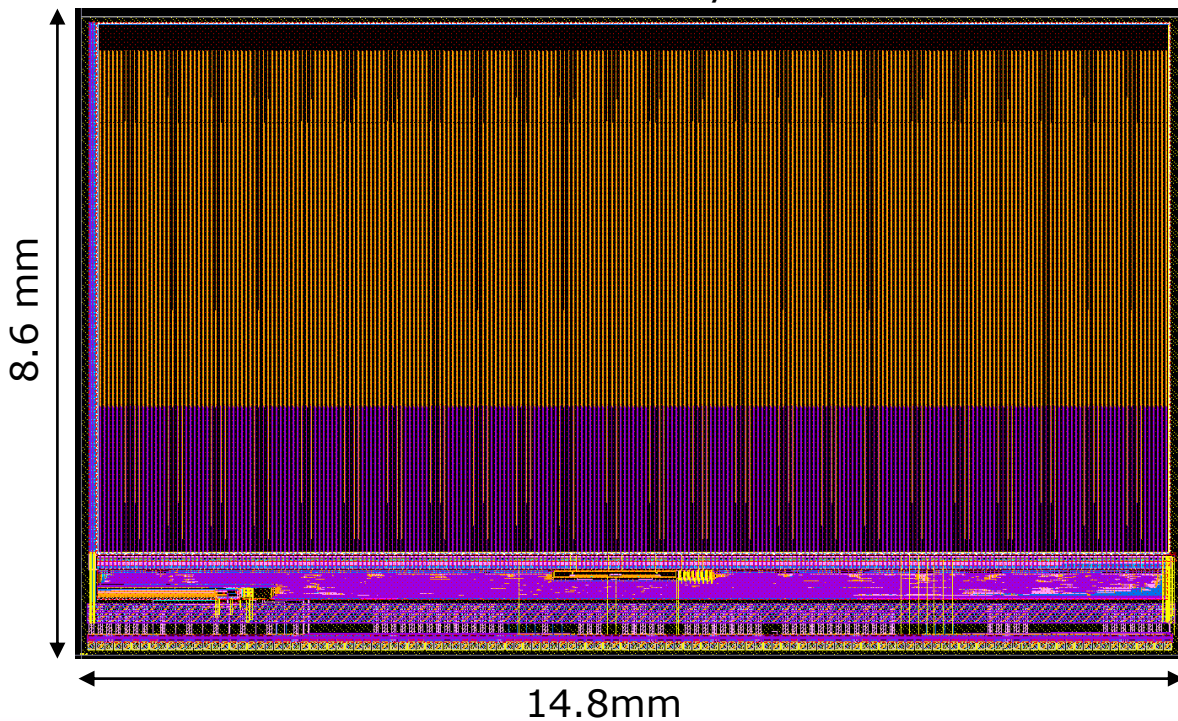
# Design specs of JadePix-4/MIC5

- JadePix-4/MIC5 optimized for fast readout and low power

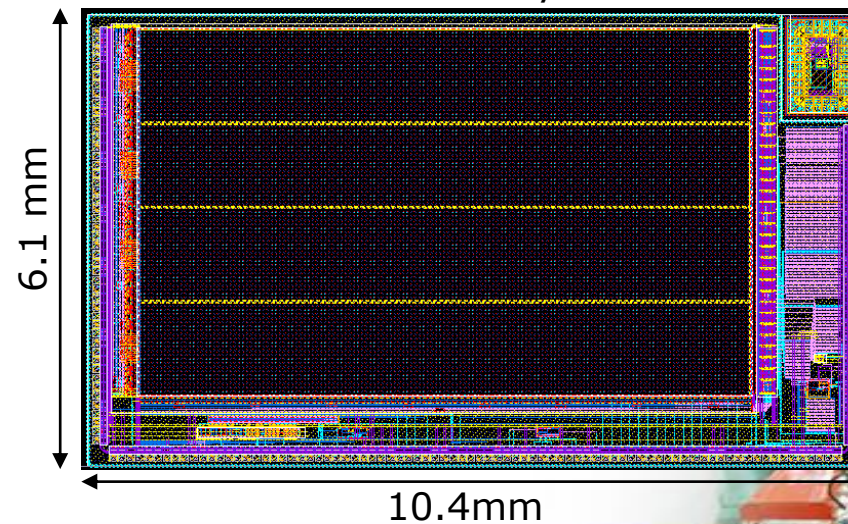
- With pixel size  $\sim 20 \mu\text{m} \times 30 \mu\text{m}$ ,
- Mask area:  $14.8 \text{ mm} \times 8.6 \text{ mm}$

	S.P. resolution	Integration time	Average power
JadePix-4	$< 5 \mu\text{m}$	$\sim 1 \mu\text{s}$	$< 100 \text{ mW/cm}^2$
JadePix-3	$< 3 \mu\text{m}$	$< 100 \mu\text{s}$	$< 100 \text{ mW/cm}^2$

JadePix-4 Layout



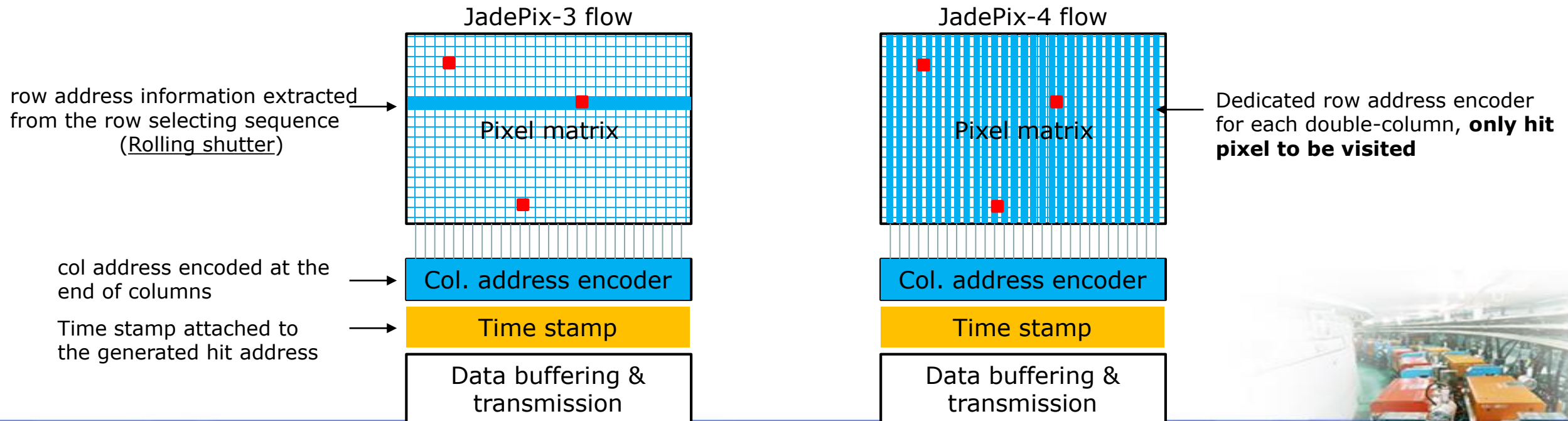
JadePix-3 Layout





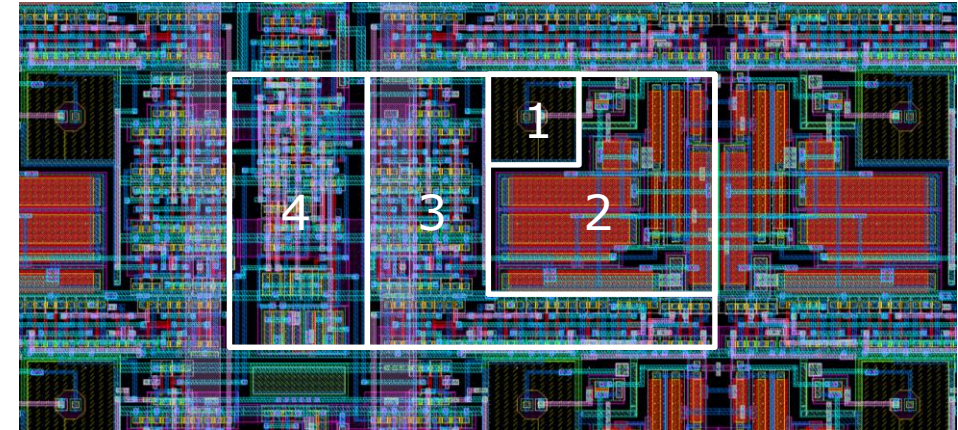
# Hit processing flow

- Hit registered in the each pixel needs fast processing
  - Hit position (col. and row address) to be encoded
  - Time stamp to be attached
  - Register to be reset for the next hit
- A major modification on the hit processing flow
  - Row address encoding embedded into the active pixel matrix, which is much faster



# Implementation

- Key component verified and reused from JadePix-3
  - Diode
  - Analog frontend
  - Hit register
- Asynchronized Encoder and Reset Decoder (AERD) \*
  - Generating col. and row address from hit pixel
  - Tracing back to reset hit pixel
- Final layout of pixel matrix
  - pixel array: 356 row × 498 col.
  - Pixel size: 20 μm × 29 μm



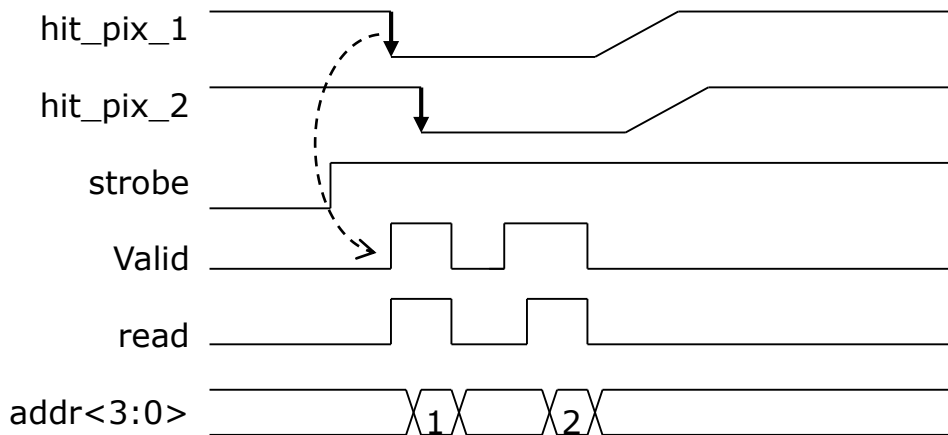
JadePix-4 pixel layout  
(MET4 and above not shown)  
1. Diode  
2. Analog frontend  
3. Digital logic  
4. AERD shared by 2 col.

\*P. Yang, etc., NIMA 785 (2015) 61-69

# Readout modes

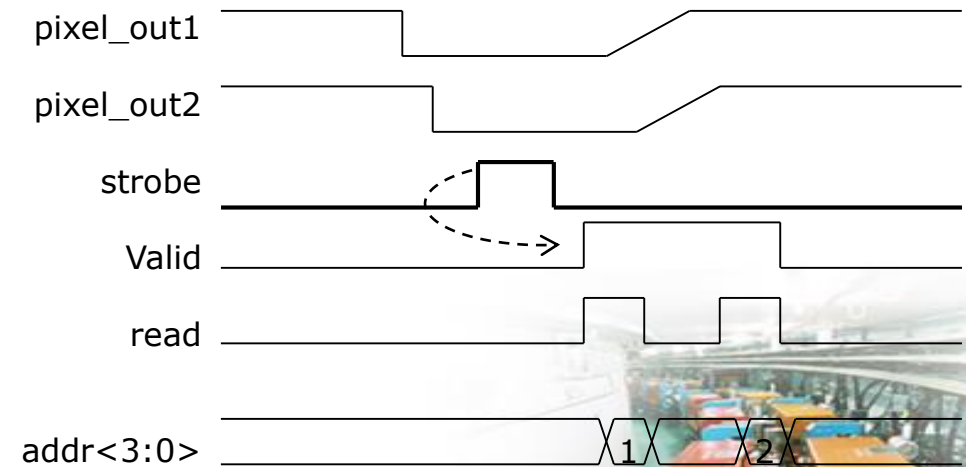
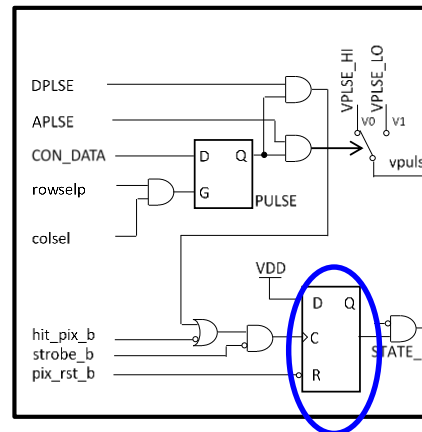
## ■ Triggerless mode

- Global gate signal, **strobe==1**
- All hits registered at their leading edge
- 0.2 hits/ $\mu$ s per double col. with the estimated hit density of inner most layer
- Occupancy 0.02% @ integration time = 1  $\mu$ s



## ■ Trigger mode

- Global gate **controlled by trigger signal**
- Hits registered only when overlapped with a trigger (analog buffer)
- Capable to handle very high hit density with a dead time for readout, 50 ns/hit



# JadePix-4/MIC5 compared with JadePix-3

- JadePix-4/MIC5 is a complementary design to the JadePix-3
  - To complete the R&D for the double-sided concept

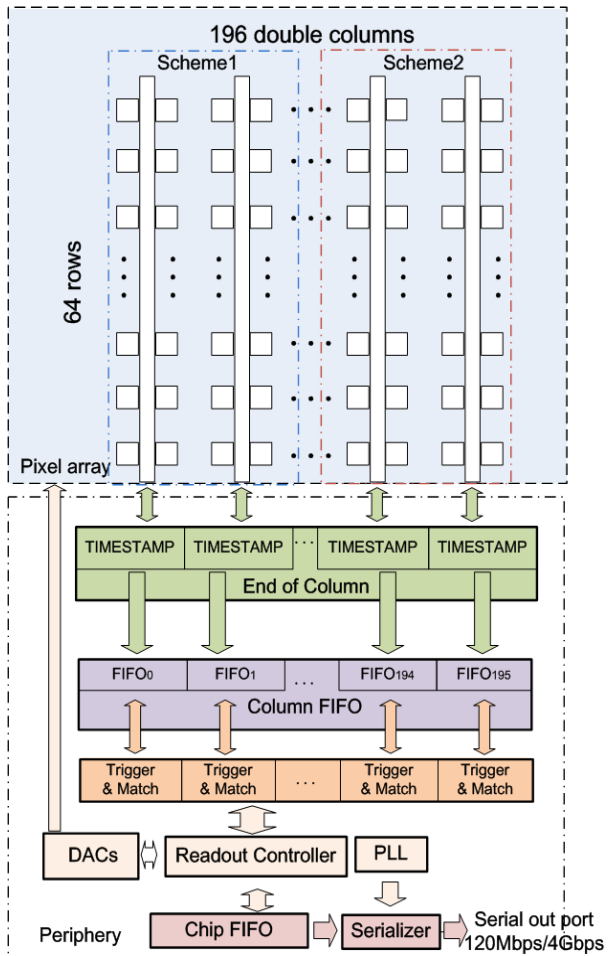
	<b>JadePix-3</b>	<b>JadePix-4/MIC5</b>
Pixel size	16 $\mu\text{m}$ $\times$ 23.1 $\mu\text{m}$	20 $\mu\text{m}$ $\times$ 29 $\mu\text{m}$
Integration time	98.3 $\mu\text{s}$	$\sim$ 1 $\mu\text{s}$
Average power	< 100 mW/cm <sup>2</sup>	< 100 mW/cm <sup>2</sup>
Pixel array	512 row $\times$ 192 col.	356 row $\times$ 498 col.
Mask area	10.4 mm $\times$ 6.1 mm	14.8 mm $\times$ 8.6 mm

- Submitted to a shared engineering run recently.





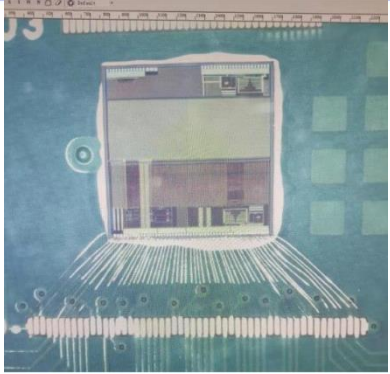
# TaichuPix architecture



- **Similar to the ATLAS ITK readout architecture: “column-drain” readout**
  - Priority based data driven readout, zero-suppression intrinsically
  - Modification: **time stamp is added at EOC** whenever a new fast-or busy signal is received
  - **Dead time:** 2 clk for each pixel (**50 ns** @40 MHz clk)
- **Two parallel pixel digital schemes**
  - ALPIDE-like: Readout speed was enhanced for 40 MHz BX
  - FE-I3-like: Fully customized layout of digital cells and address decoder for smaller area
- **2-level FIFO architecture**
  - L1 FIFO: In column level, to de-randomize the injecting charge
  - L2 FIFO: Chip level, to match the in/out data rate between the core and interface
- **Trigger readout**
  - Make the data rate in a reasonable range
  - Data coincidence by time stamp, only matched event will be readout



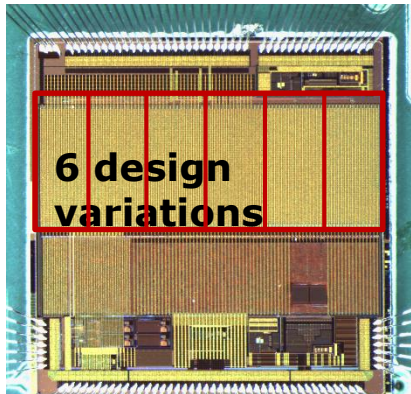
# TaichuPix small prototypes overview



TaichuPix-1

Chip size: 5 mm × 5 mm

Pixel size: 25 μm × 25 μm



TaichuPix-2

Chip size: 5 mm × 5 mm

Pixel size: 25 μm × 25 μm

## ■ Two MPW chips were fabricated and verified

- TaichuPix-1: 2019.06~2019.11
- TaichuPix-2: 2020.02~2020.06

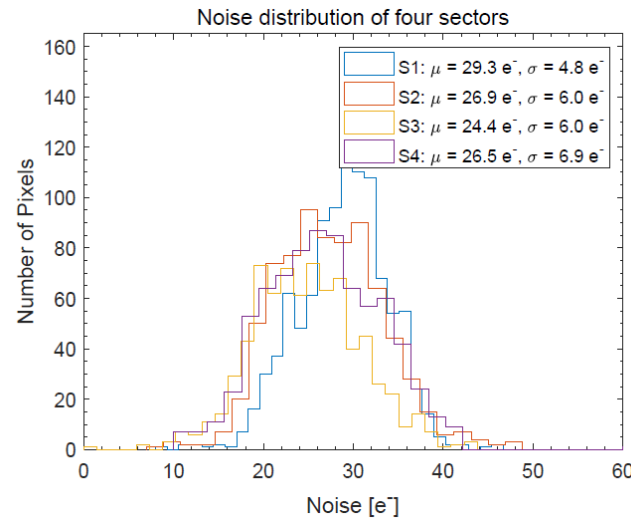
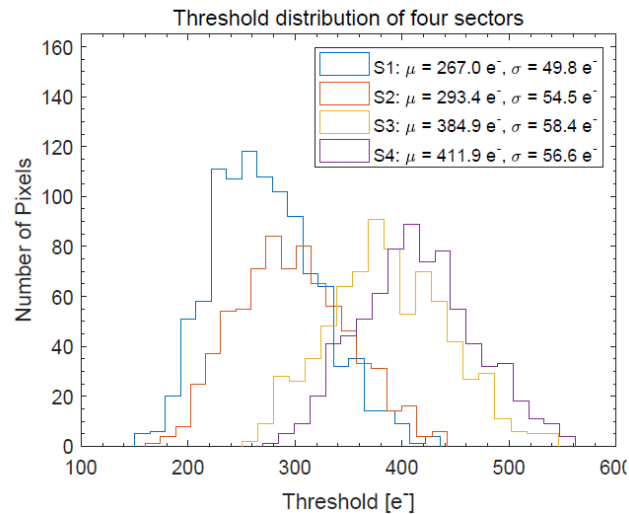
## ■ Chip size 5 mm×5 mm with standalone features

- In-pixel circuitry:
  - Continuously active front-end
  - Two digital schemes, with masking & testing config. logics
- A full functional pixel array (64×192 pixels)
- Periphery logics
  - Fully integrated logics for the **data-driven readout**
  - Fully digital control of the chip configuration
- Auxiliary blocks for standalone operation
  - **High speed data interface** up to 4 Gbps
  - On-chip bias generation
  - Power management with LDOs
  - IO placement in the final ladder manner
    - Multiple chip interconnection features included

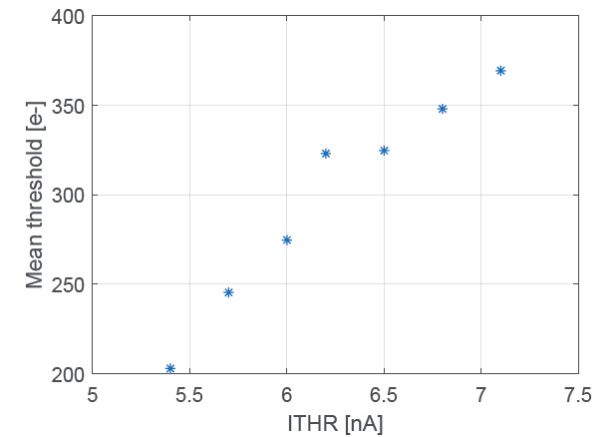


# Performance of threshold and noise of TaichuPix2

- Pixel array includes 4 sectors with different transistor parameters/layout for analog front-end, S1 chosen for the full-scale design.
- Threshold can be tuned by changing 'ITHR' (a global current bias)



Mean threshold vs. Threshold current ITHR

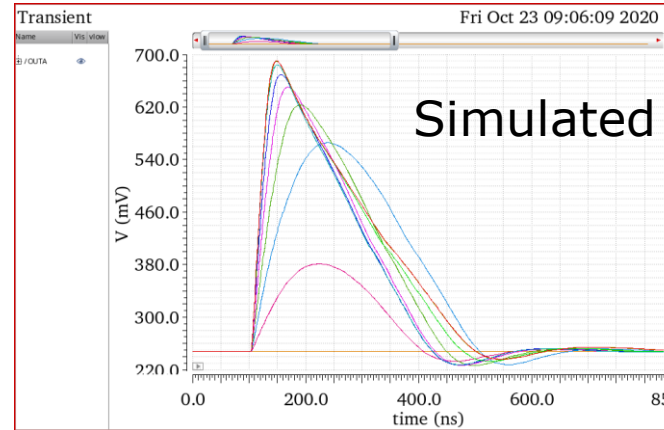
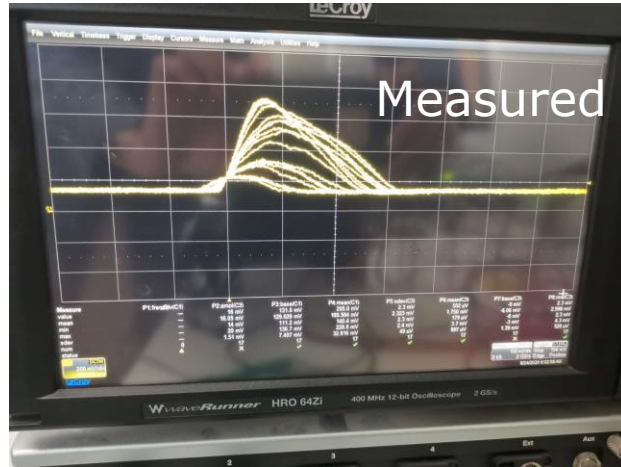


Chip4	Threshold Mean ( $e^-$ )	Threshold rms ( $e^-$ )	Temporal noise ( $e^-$ )	Total equivalent noise ( $e^-$ )
S1	267.0	49.8	29.3	57.8
S2	293.4	54.5	26.9	60.8
S3	384.9	58.4	24.4	63.3
S4	411.9	56.6	26.5	62.5

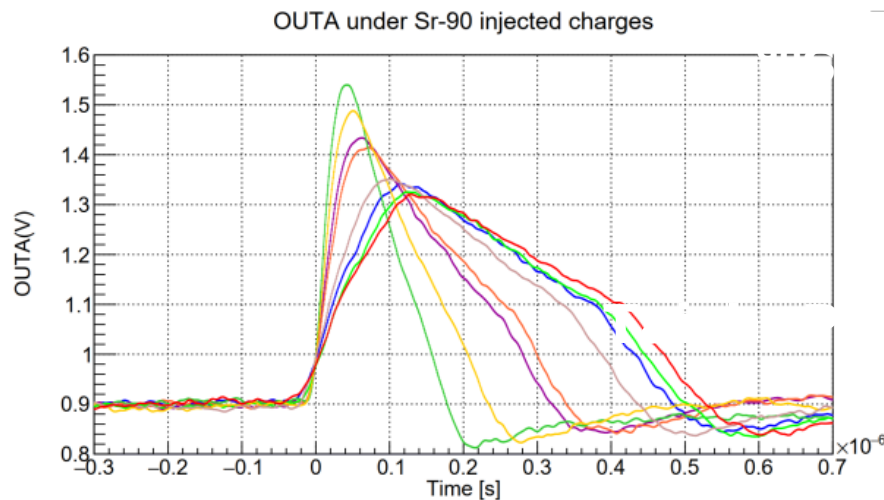


# TaichuPix response to radioactive source

## ■ Functionality of TaichuPix1&2 proved

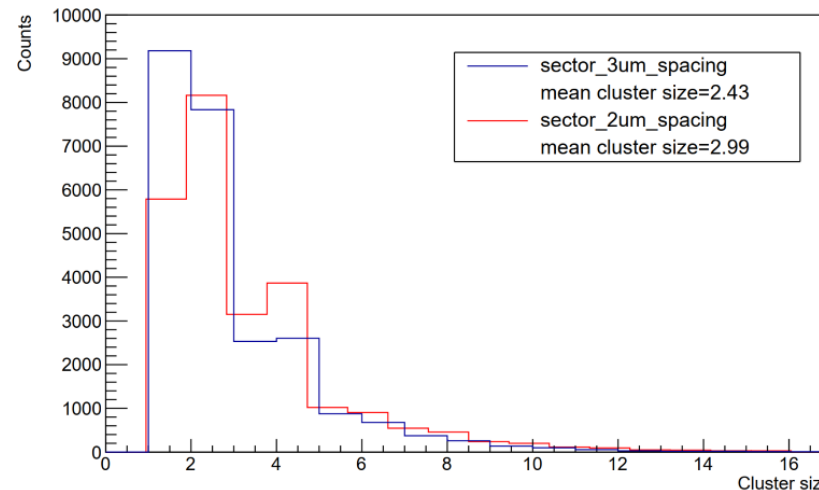


## TaichuPix2 response to X-ray tube (cutting energy @ 6keV)



TaichuPix1 response to  $^{90}\text{Sr}$  exposure

Cluster Distribution

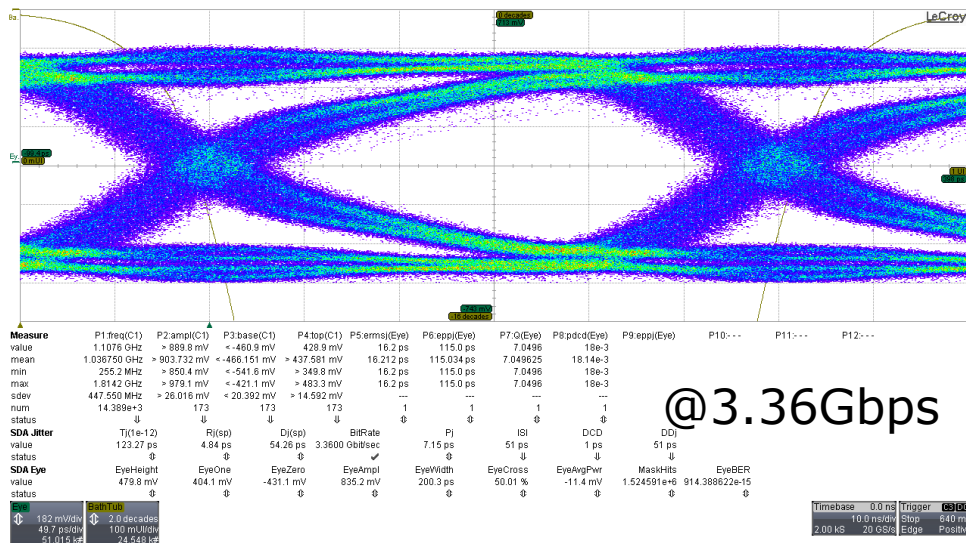
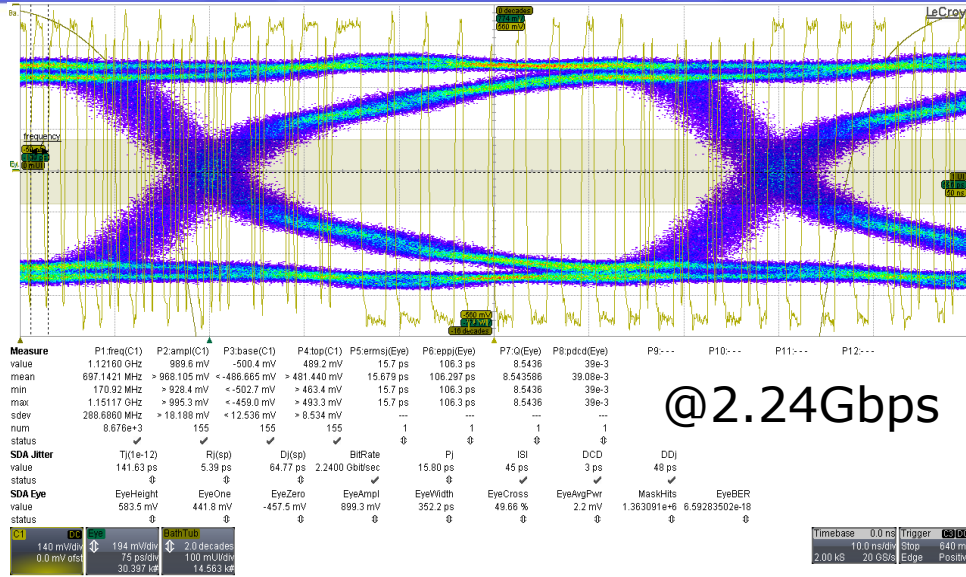


TaichuPix1 cluster size to  $^{90}\text{Sr}$  exposure





# Test of the data interface



Bit rate	2.24Gbps	3.36Gbps	4.48Gbps
Clk freq	1.12GHz	1.68GHz	2.24GHz
BER	6.59e-18	9.14e-13	3.23e-5
Tj@e-12	141.63ps	123.27ps	147.14ps
Rj	5.39ps	4.84ps	5.35ps
Dj	64.77ps	54.26ps	70.90ps

- Data readout in DDR mode
- Data interface was tested by the on-chip PRBS source, a high speed oscilloscope (@16Gsps), and code stream verified in FPGA
- **BER qualified till 3.36 Gbps, failed at 4.48 Gbps**
- Concerning the highest data rate for triggerless at 4 Gbps, at least 2 SER interface ports needed
- Thus bit rate @2.24 Gbps is safe and power optimized



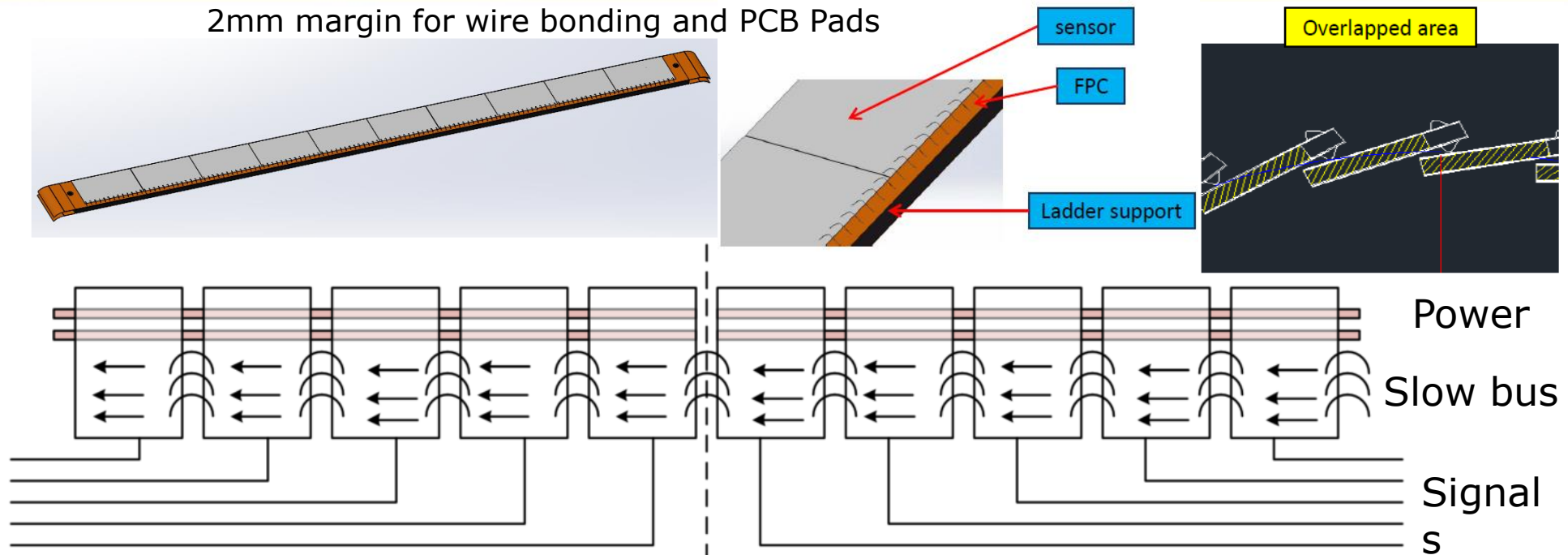
# Overview of the full scale prototype



1. Pixel array 1024\*512
2. Periphery
3. DAC & Bias generation
4. Data interface
5. LDO (test blocks)
6. **Chip inter-connection features**
7. Scribe-able top power connection features

- Process: 180 nm CMOS Imaging Sensor process (7 metal layers)
- Pixel cell copied exactly from MPW + scaled logic with new layout Periphery + debugged/improved blocks + enhanced power network

# Flex cable design consideration



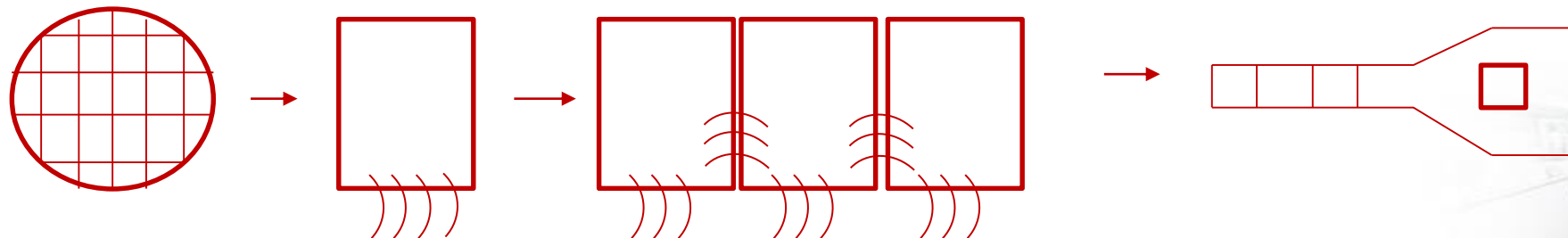
## ■ Design goals & considerations for the Flex PCB

- Minimum material budget
  - Minimum dead zone extension, limited height of PCB
    - Minimum set of signals on Flex
    - Inter-chip connection for slow controls through wire bonding → save some space & metal on PCB
  - Robust power supply
- Manufacturability



# Testability design & test plan consideration

- **All test features reserved, while the connection IOs will be reduced at different stages depending on chip test & study results**
  - Analog probe signals at the top part, accessible from the top pads
  - When mounted on ladder, only minimum self test possibilities can be reserved
- 1. **Probe Card design for the wafer test**
  - For all the pads at both sides
- 2. **Single chip test board design**
  - Designed with all the test features for the chip functional study
- 3. **Multiple chip test board for the ladder debugging**
  - Designed following the same manner as the ladder but on PCB
  - Signals and power supplies will be limited just with the ladder's dimension
  - Extra test signals can be connected to the extended area, to help debugging
- 4. **The real flex cable design for the ladder**
  - Core design and lessons will be exported from 3





# Summary and outlook

- Progress made on the JadePix and TaichuPix development
  - JadePix-4 arose as a complementary design to the JadePix-3
  - TaichuPix full scale completed based on the TaichuPix-2 results
- Is it possible to converge into one design at some point?
  - Both are expecting to migrate to a deeper sub-micro process
  - Established capability to synthesize various design choices for one optimized scheme
- Next generation of CMOS pixel sensor technology
  - 65 nm CMOS technology is being evaluated in Europe
  - Survey on domestic foundry is needed in light of international export control



# Pixel sensor teams

## ■ JadePix-3/4

- IHEP: Ying Zhang, Yang Zhou, Zhigang Wu (graduated), Jing Dong, Wenhao Dong/USTC, Chunhao Tian/USTC, Yunpeng Lu, Qun Ouyang
- CCNU: Yang Ping, Weiping Ren, Le Xiao, Di Guo, Chenxing Meng (graduated), Anyang Xu (graduated), Sheng Dong, Hulin Wang, Xiangming Sun
- SDU: Liang Zhang
- Dalian Minzu Univ: Zhan Shi

## ■ TaichuPix

- IHEP: Wei Wei, Ying Zhang Xiaoting Li, Jun Hu, Zhijun Liang, Joao Guimaraes da Costa
- CCNU/ IFAE: Tianya Wu, Raimon Casanova, Sebastian Grinstein
- NWPU: Xiaomin Wei, Jia Wang
- SDU: Liang Zhang, Jianing Dong, Long Li

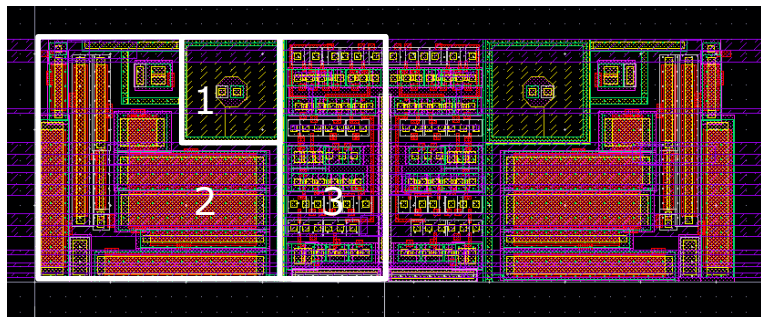
**Thank you for your time!**



## Backup Slides



# Small pixel implemented in the JadePix3



Minimal pixel footprint: **16  $\mu\text{m}$  \* 23.11  $\mu\text{m}$**

- 1: Sensing diode
- 2: Analog frontend
- 3: digital frontend

## ■ Small footprint

- Sensing diode of minimized geometry verified on JadePix1
- Frontend with **tradeoff** between layout area and FPN\*

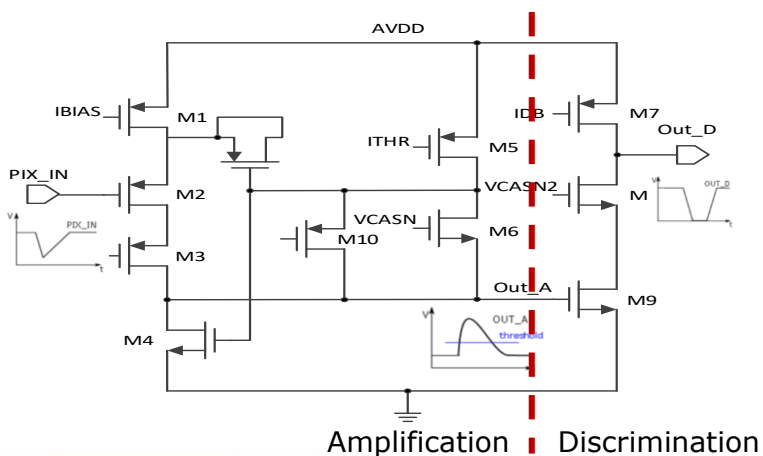
## ■ Fix $\varphi$ direction to **16 $\mu\text{m}$** and allow the $z^*$ to vary

- 3 variants of digital frontend
- D-FlipFlop vs RS-latch

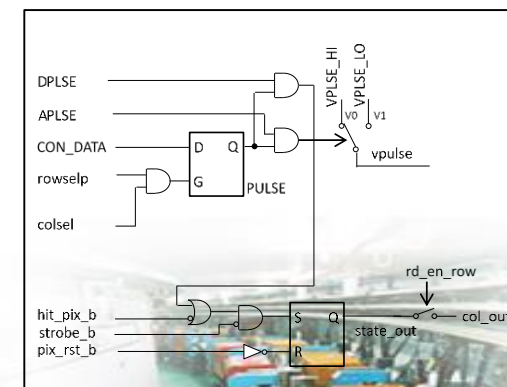
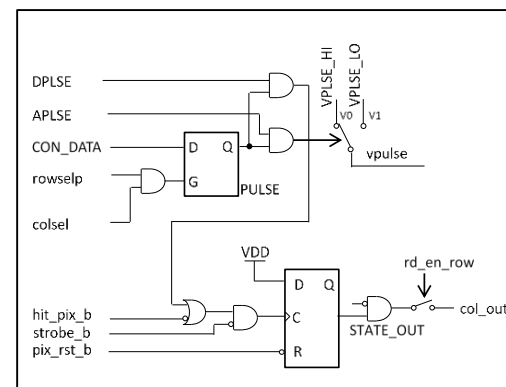
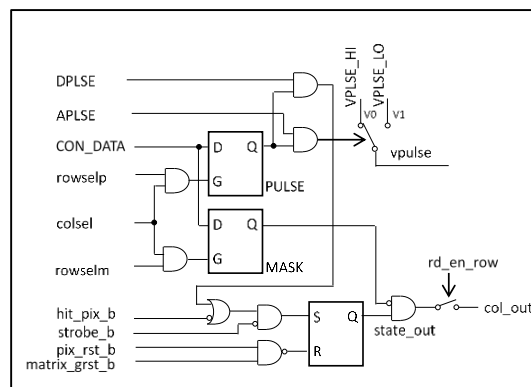
## ■ Mirrored layout to share bias lines between two columns

\* D. Kim, etc. 2016 JINST 11 C02042

analog frontend

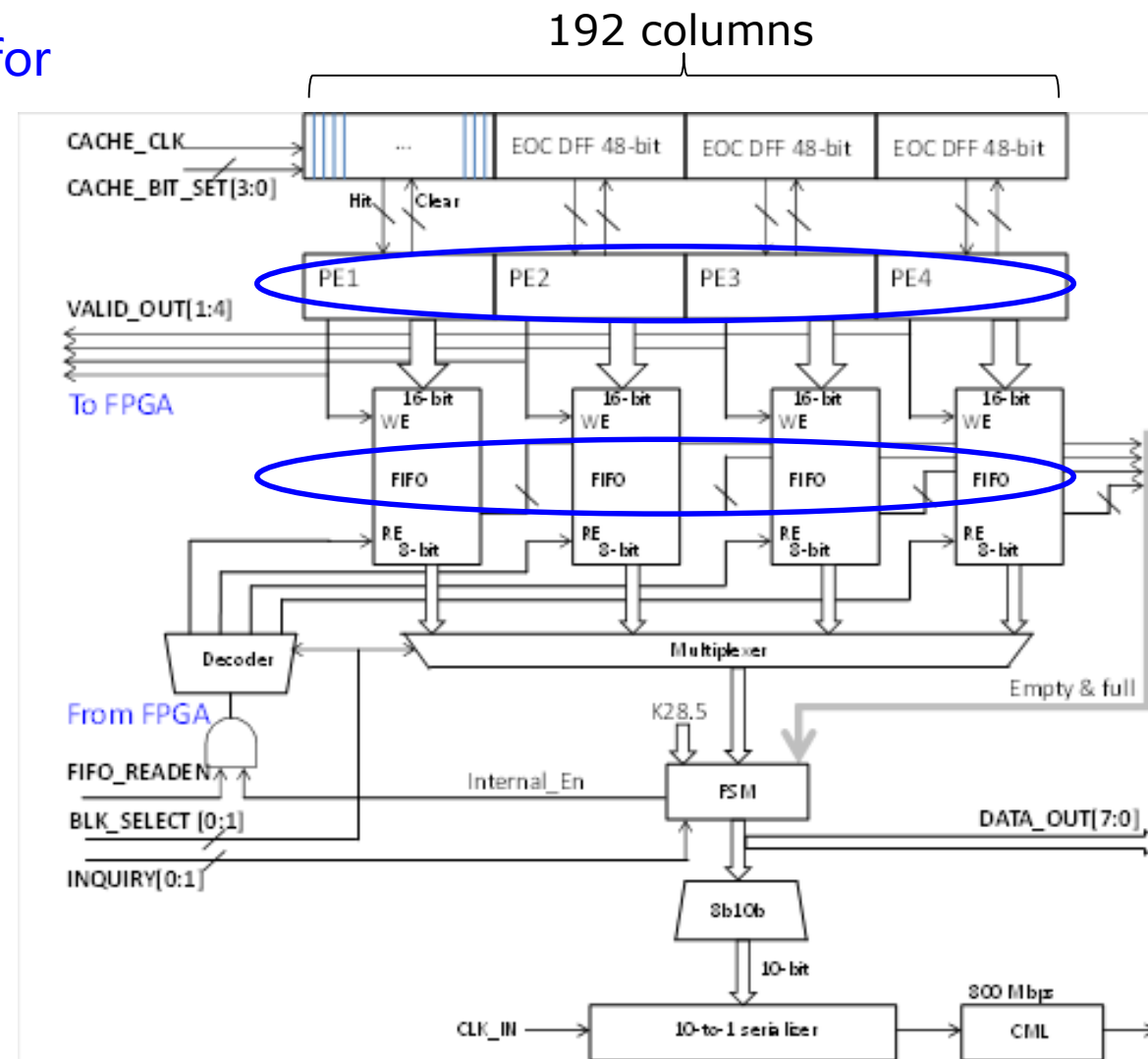


3 variants of digital frontend



# Lower power design in the JadePix3

- A low power frontend of **20 nA static current**, equivalent to 9 mW/cm<sup>2</sup>
  - Except for the sector 3, where 60 nA used for the comparison of radiation tolerance
- Zero suppression at the end of column
  - **Priority Encoded (PE)** address of HIT pixel
- Data buffering
  - 4 parallel FIFOs \* 48 depth
  - Multiplexer controlled by FPGA
  - Allow the **test of readout strategy**
- Extensible along with the matrix sectors

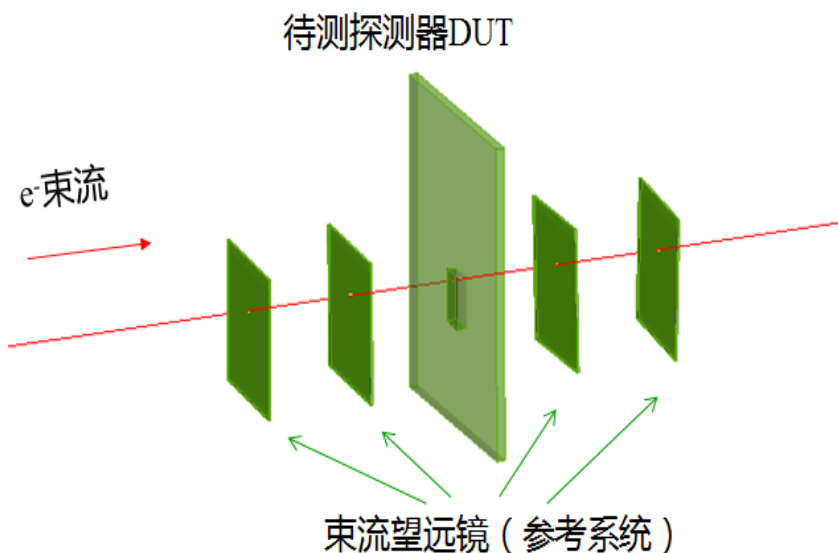




# Measurement method of position resolution

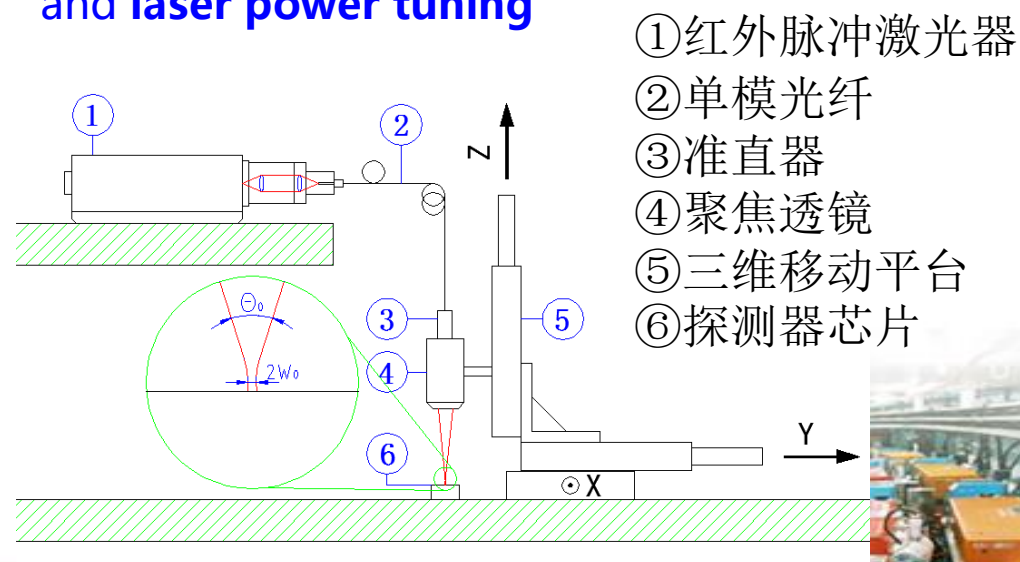
## Charged particle beam

- Random hit position on the full matrix
  - One hit per particle
  - Reconstructed reference position by beam telescope
  - $\sigma$  of residual = measured - reference
  - Cluster size can be adjusted by threshold tuning



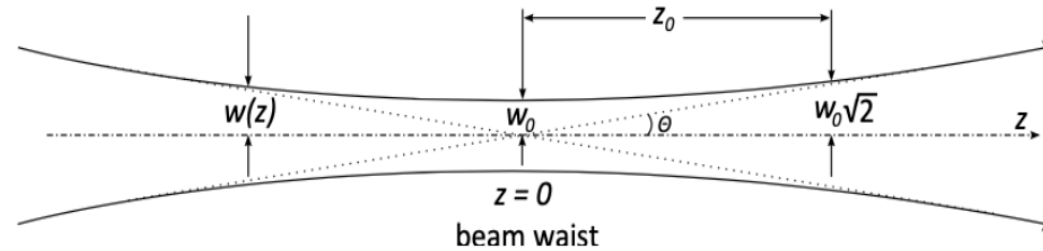
## Pulsed laser beam

- Well controlled **scan of laser position** on a **single pixel**
  - One hit per laser pulse
  - Reference position given by the 3-D motion stage
  - $\sigma$  of residual = measured - reference
  - Cluster size can be adjusted by threshold tuning and **laser power tuning**



# Laser beam characteristics

Hulin WANG, Shen DONG, Yunpeng LU



## ■ Laser beam characterization

- Wavelength: 1064 nm
- Beam waist  $w_0 \sim 1.7 \mu\text{m}$
- Rayleigh range  $z_0 \sim 8.5 \mu\text{m}$
- Divergence Angle  $\theta = \sim 11^\circ$
- Laser pulse duration  $\sim 100 \text{ ps}$

## ■ Laser power tune and coarse calibration

- 0% : maximum power; 100% : minimum power
- For final results, use 92.7%, 92.9%, 93.3%, 93.5%, 93.7%
- 92.7%  $\sim 4 \times$  **threshold** (threshold set to  $\sim 220 \text{ e-}$ )
- 93.7%  $\sim 2 \times$  **threshold**

